

Search Notes 	Application/Control No. 10/066,024	Applicant(s)/Patent under Reexamination BUER ET AL.
Examiner Pablo N. Tran	Art Unit 2685	

SEARCHED			
Class	Subclass	Date	Examiner
455	326	11/12/17	PJ
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	189.1		
	190.1		
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Application/Control No.

10/066,024

Examiner

Pablo N. Tran

Applicant(s)/Patent under
Reexamination

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2685

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455	353	11/05/05	PJL
333	1.1		
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331	96		
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343	700MS		
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	853		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR